

2N7002E

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2N7002E

60V N-Channel Enhancement Mode MOSFET

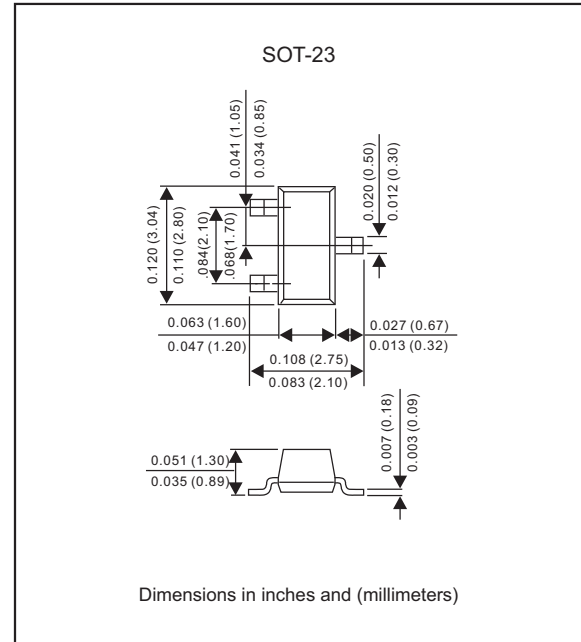
Features

- 60V / 0.50A , $R_{DS(ON)} = 5.0\Omega @ V_{GS}=10V$
- 60V / 0.30A , $R_{DS(ON)} = 5.5\Omega @ V_{GS}=4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability
- High density cell design for low $R_{DS(ON)}$
- Voltage controlled small signal switch
- Rugged and reliable
- High saturation current capability
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds
- In compliance with EU RoHS 2011/65/EU directives
- Suffix "-H" indicates Halogen-free part, ex. 2N7002E-H

Mechanical data

- Epoxy:UL94-V0 rated flame retardant
- Case : Molded plastic, SOT-23
- Terminals : Solder plated, solderable per MIL-STD-750, Method 2026
- Mounting Position : Any
- Weight : Approximated 0.0084 gram

Package outline



Maximum ratings (AT $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Conditions	Symbol	MIN.	TYP.	MAX.	Unit
Drain-source voltage		V_{DSS}			60	V
Drain current - continuous	$T_A=25^\circ\text{C}$	I_D			300	mA
-pulsed(Note 1)					1200	
Gate-source voltage - continuous		V_{GSS}			± 20	V
Gate-source voltage - non repetitive	$t_p < 50\mu\text{s}$				± 40	
Power dissipation	$T_A=25^\circ\text{C}$	P_D			350	mW
Operating junction and storage temperature range		T_J, T_{STG}	-55		+150	$^\circ\text{C}$
Thermal resistance	Junction to ambient	$R_{\theta JA}$			375	$^\circ\text{C/W}$

Note 1: Pulse width limited by safe operating area

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Electrical characteristics (AT $T_A=25^{\circ}\text{C}$ unless otherwise noted)**OFF CHARACTERISTIC**

Parameter	Conditions	Symbol	MIN.	TYP.	MAX.	Unit
Drain-source breakdown voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	B_{VDS}	60			V
Zero gate voltage drain current	$V_{DS}=60\text{V}$, $V_{GS}=0\text{V}$	I_{DSS}			1.0	μA
	$V_{DS}=60\text{V}$, $V_{GS}=0\text{V}$, $T_J=125^{\circ}\text{C}$				10	μA
Gate-body leakage, forward	$V_{DS}=0\text{V}$, $V_{GS}=20\text{V}$	I_{GSSF}			100	nA
Gate-body leakage, reverse	$V_{DS}=0\text{V}$, $V_{GS}=-20\text{V}$	I_{GSSR}			-100	nA

ON CHARACTERISTIC (Note1)

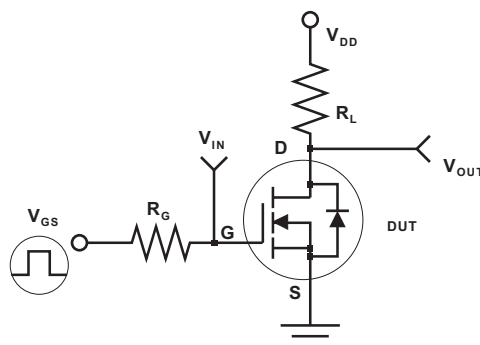
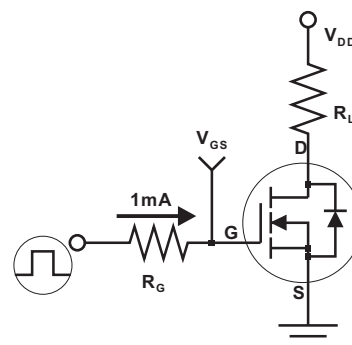
Gate threshold voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	$V_{GS(th)}$	1.0	1.7	2.5	V
Static drain-source on-resistance	$V_{GS}=10\text{V}$, $I_D=500\text{mA}$ $V_{GS}=4.5\text{V}$, $I_D=300\text{mA}$	$R_{DS(on)}$		2.5	5.0	Ω
				3.3	5.5	
Source-drain current		I_{SD}			0.35	A
Source-drain current (pulsed)		$I_{SDM(2)}$			1.4	A
Forward trans-conductance	$V_{DS}=10\text{V}$, $I_D=500\text{mA}$	$G_{FS(1)}$		0.6		S
Diode forward Voltage	$V_{GS}=0\text{V}$, $I_S=0.12\text{mA}$	$V_{SD(1)}$		0.85	1.5	V

DYNAMIC CHARACTERISTICS

Input capacitance	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	C _{iss}		43		pF
Output capacitance		C _{oss}		20		
Reverse transfer capacitance		C _{rss}		6.0		
Total gate charge	V _{DD} =30V, I _D =1A ,V _{GS} =5V	Q _g		1.4	2.0	nC
Gate-source charge		Q _{gs}		0.8		
Gate-drain charge		Q _{gd}		0.5		
Turn-on time	V _{DD} =30V, R _G =4.7Ω, V _{GS} =4.5V, I _D =500mA	t _{d(on)}		6.0		ns
Turn-off time		t _r		5.0		
		t _{d(off)}		15		
		t _r		6.0		

(1) Pulsed: Pulse duration=300 μs , duty cycle1.5%.

(2) Pulse width limited by safe operating area.

**Switching
Test Circuit****Gate Charge
Test Circuit**

Rating and characteristic curves (2N7002E)

FIG.1 Transfer Characteristics

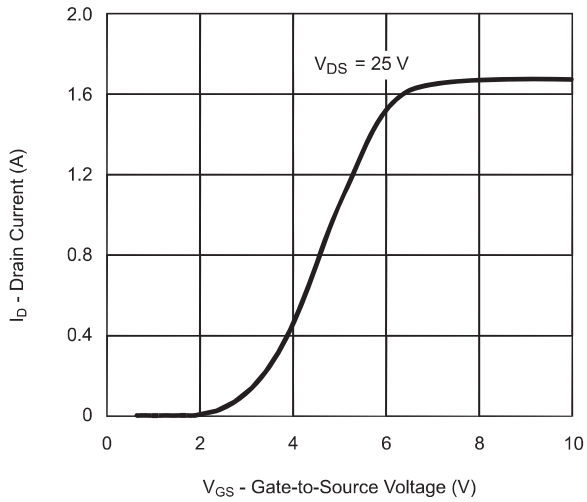


FIG.2 On-Resistance vs. Drain Current

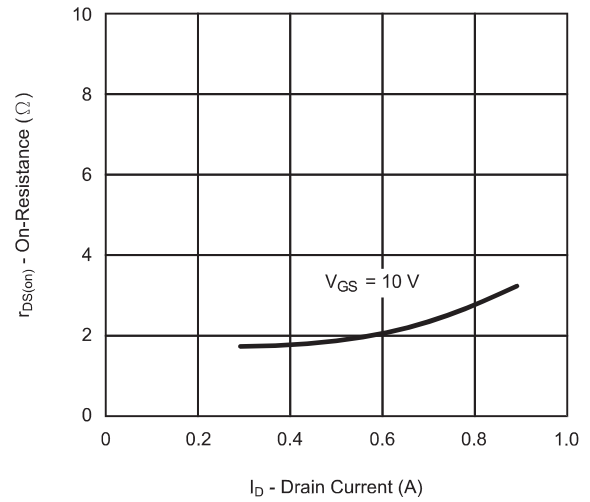


FIG.3 Capacitance

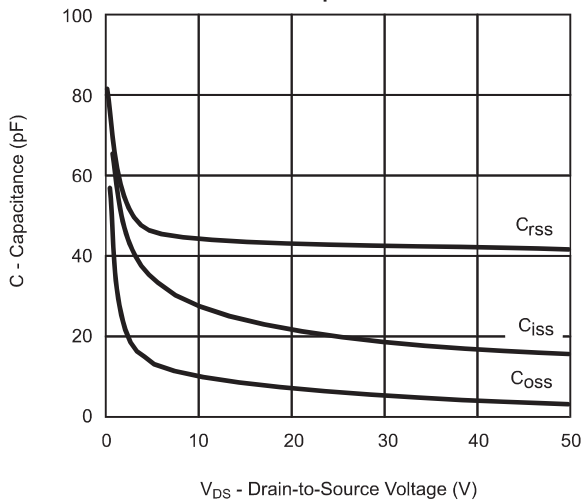


FIG.4 On-Resistance vs. Gate-to-Source Voltage

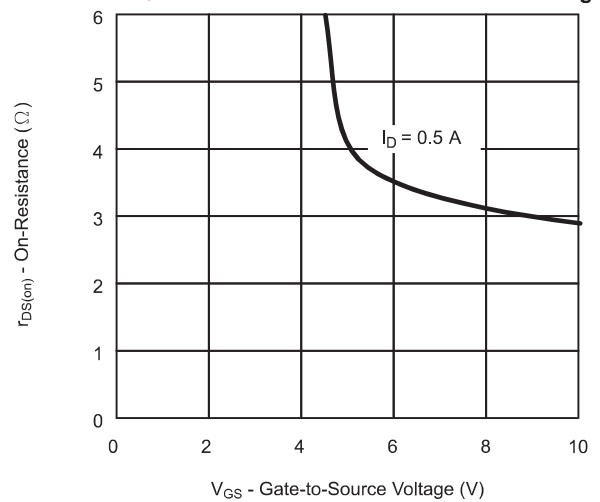


FIG.5 Threshold Voltage

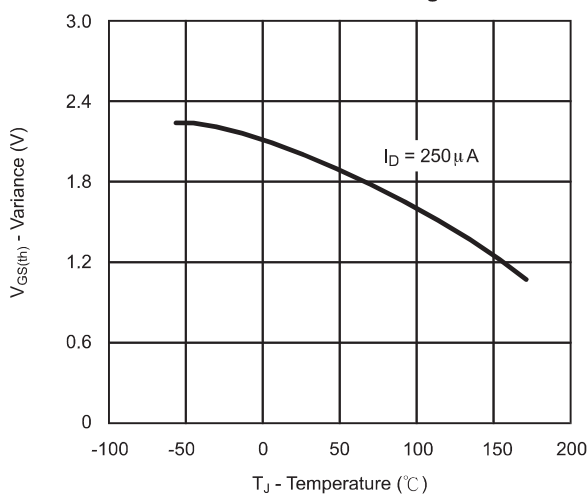
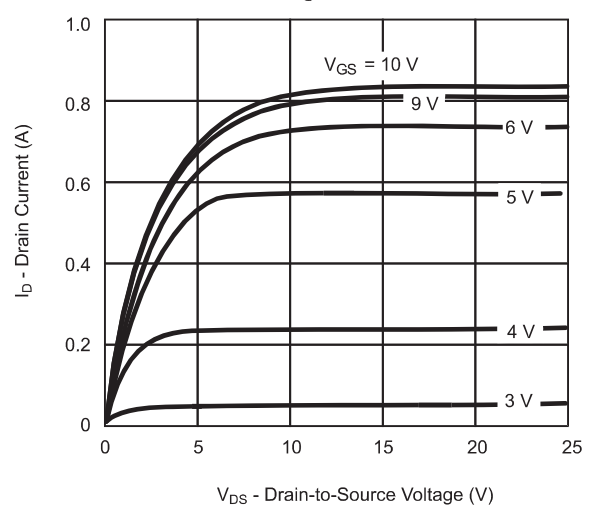


FIG.6 On-Region Characteristics



Rating and characteristic curves (2N7002E)

FIG.7 Gate Charge

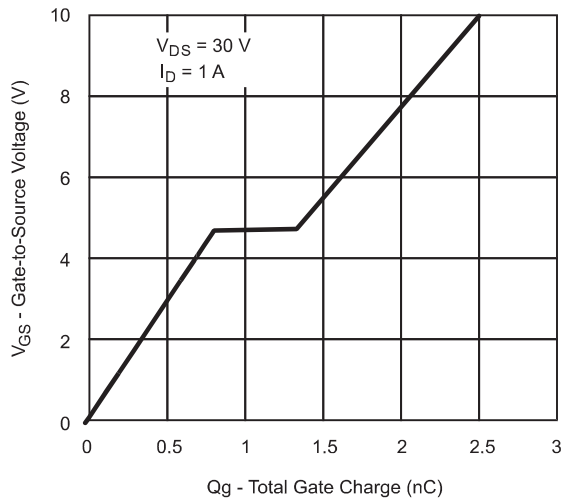


FIG.8 On-Resistance vs. Drain Current

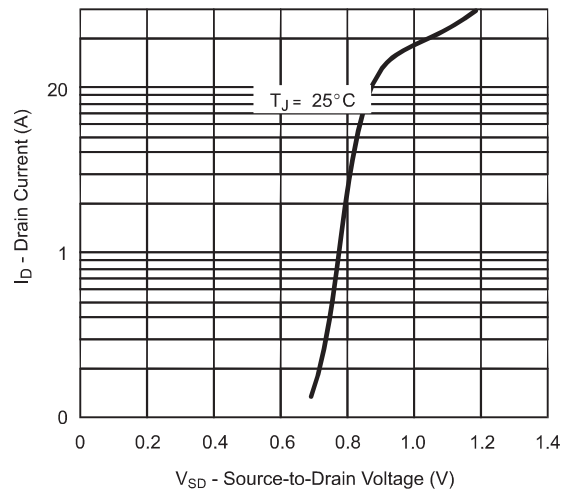


FIG.9 Maximum Forward Biased Safe Operating Area

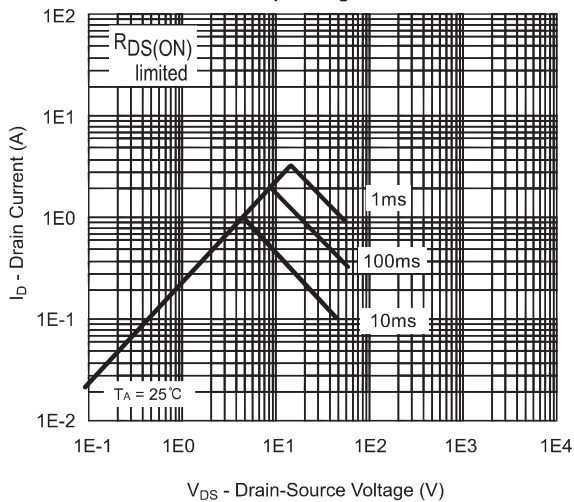
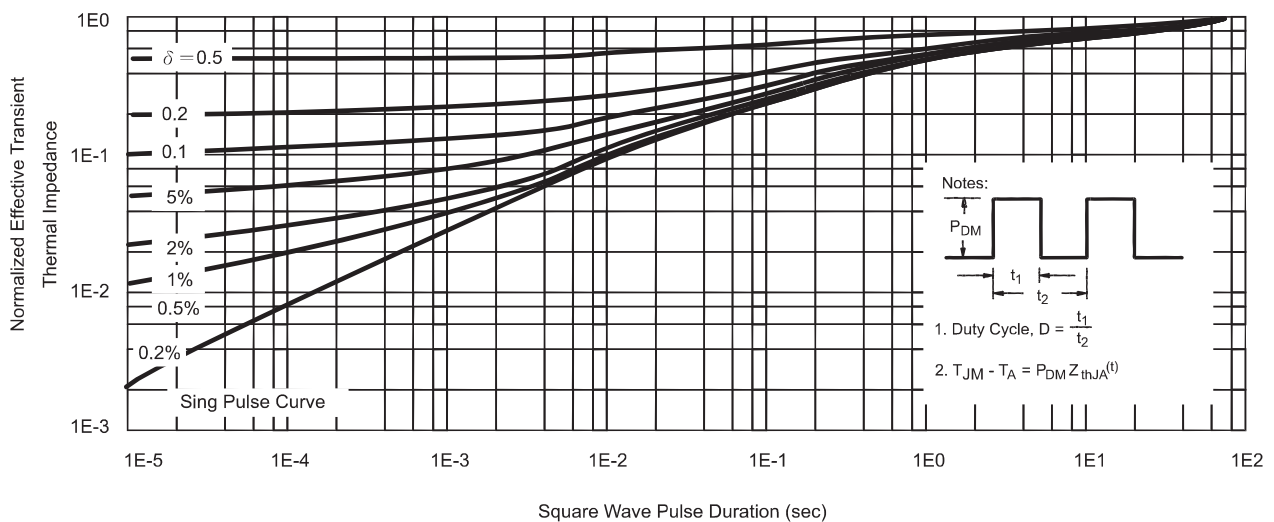
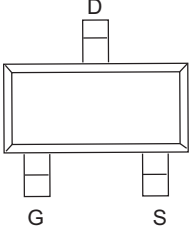
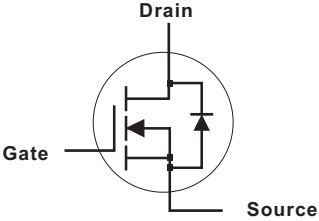


FIG.10 Normalized Thermal Transient Impedance, Junction-to-Ambient



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Pinning information

Pin	Simplified outline	Symbol
PinD Drain PinG Gate PinS Source		

Marking

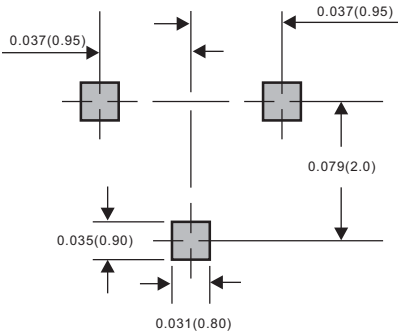
Type number	Marking code
2N7002E	702Σ (Note 1)
	E73Σ (Note 1)

Note 1: Σ = Month code

Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Odd Year	1	2	3	4	5	6	7	8	9	T	V	C
Even Year	E	F	H	J	K	L	N	P	U	X	Y	Z

Suggested solder pad layout

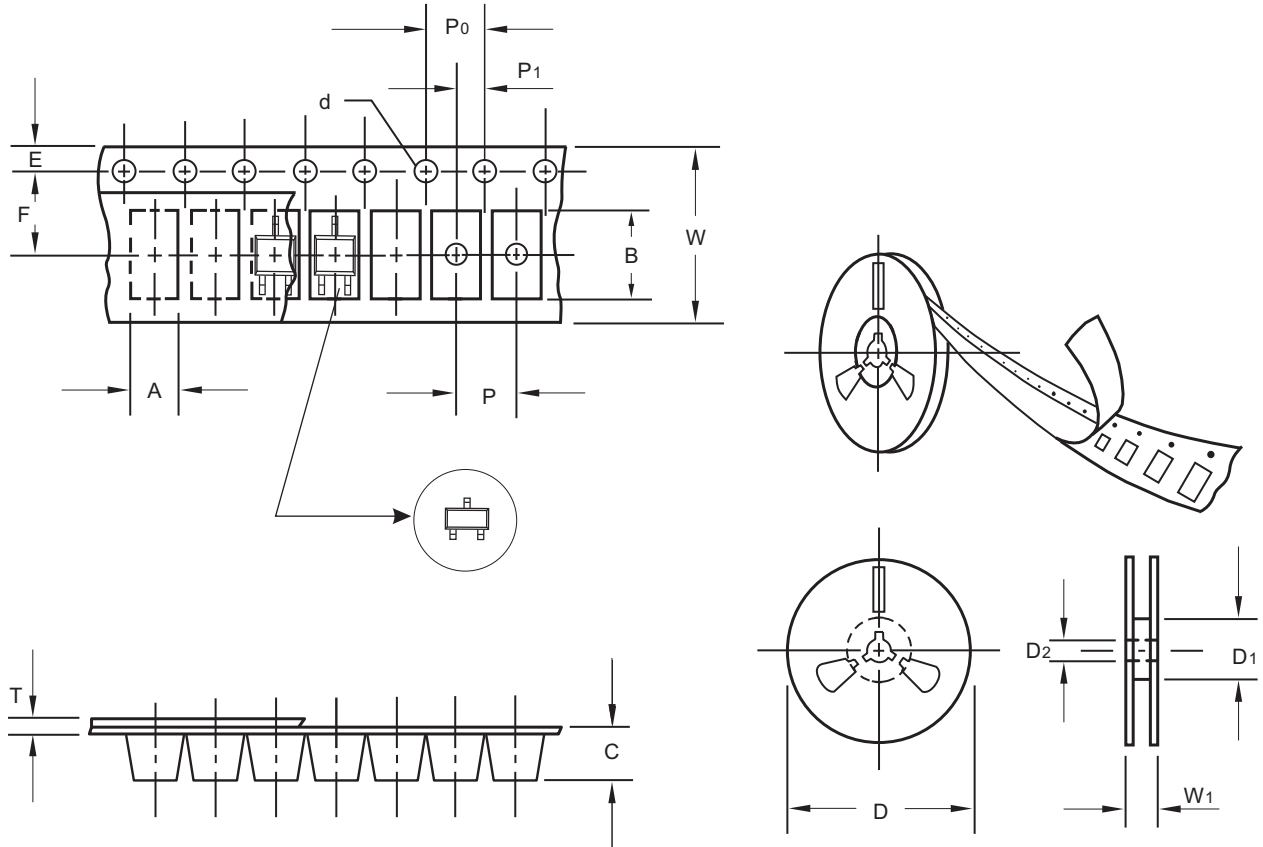
SOT-23



Dimensions in inches and (millimeters)

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Packing information



unit:mm

Item	Symbol	Tolerance	SOT-23
Carrier width	A	0.1	3.15
Carrier length	B	0.1	2.77
Carrier depth	C	0.1	1.22
Sprocket hole	d	0.1	1.50
13" Reel outside diameter	D	2.0	-
13" Reel inner diameter	D1	min	-
7" Reel outside diameter	D	2.0	178.00
7" Reel inner diameter	D1	min	55.00
Feed hole diameter	D2	0.5	13.00
Sprocket hole position	E	0.1	1.75
Punch hole position	F	0.1	3.50
Punch hole pitch	P	0.1	4.00
Sprocket hole pitch	P0	0.1	4.00
Embossment center	P1	0.1	2.00
Overall tape thickness	T	0.1	0.23
Tape width	W	0.3	8.00
Reel width	W1	1.0	12.0

Note: Devices are packed in accordance with EIA standard RS-481-A and specifications listed above.

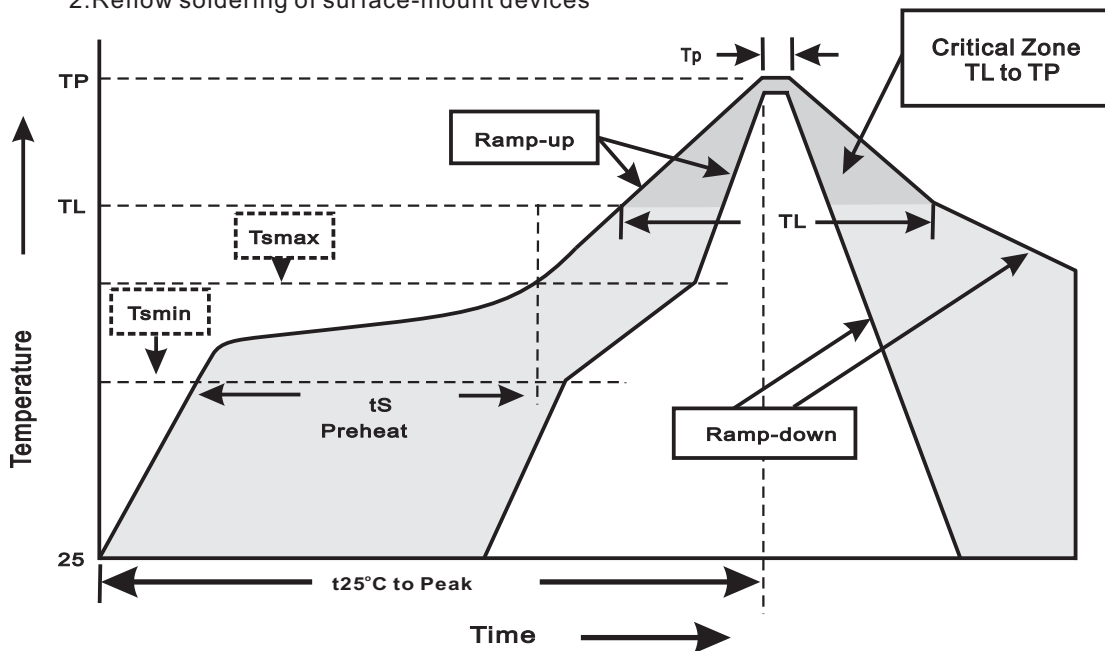
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Reel packing

PACKAGE	REEL SIZE	REEL (pcs)	COMPONENT SPACING (m/m)	BOX (pcs)	INNER BOX (m/m)	REEL DIA, (m/m)	CARTON SIZE (m/m)	CARTON (pcs)	APPROX. GROSS WEIGHT (kg)
SOT-23	7"	3,000	4.0	30,000	183*123*183	178	382*257*387	240,000	11.6

Suggested thermal profiles for soldering processes

- 1.Storage environment: Temperature=5°C~40°C Humidity=55%±25%
- 2.Reflow soldering of surface-mount devices



3.Reflow soldering

Profile Feature	Soldering Condition
Average ramp-up rate(T _L to T _P)	<3°C/sec
Preheat -Temperature Min(T _{smmin}) -Temperature Max(T _{smmax}) -Time(min to max)(t _s)	150°C 200°C 60~120sec
T _{smmax} to T _L -Ramp-upRate	<3°C/sec
Time maintained above: -Temperature(T _L) -Time(t _L)	217°C 60~260sec
Peak Temperature(T _P)	255°C-0/+5°C
Time within 5°C of actual Peak Temperature(t _P)	10~30sec
Ramp-down Rate	<6°C/sec
Time 25°C to Peak Temperature	<6minutes

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High reliability test capabilities

Item Test	Conditions	Reference
1. Solder Resistance	at $260 \pm 5^{\circ}\text{C}$ for 10 sec.	MIL-STD-750D METHOD-2031
2. Solderability	at $245 \pm 5^{\circ}\text{C}$ for 5 sec.	MIL-STD-202F METHOD-208
3. High Temperature Reverse Bias	$V_{DS} = 0.8 \times BV_{DSS}$, at $T_J = 150^{\circ}\text{C}$ for 168 hrs.	MIL-STD-750D METHOD-1038
4. Pressure Cooker	$15P_{SIG}$ at $T_A = 121^{\circ}\text{C}$ 100%RH for 4 hrs.	JESD22-A102
5. Temperature Cycling	-55°C to $+125^{\circ}\text{C}$ dwelled for 30 min total 10 cycles.	MIL-STD-750D METHOD-1051
6. Humidity	at $T_A = 85^{\circ}\text{C}$, 85%RH for 1000 hrs.	MIL-STD-750D METHOD-1021
7. High Temperature Storage Life	at $T_A = 175^{\circ}\text{C}$ for 1000 hrs.	MIL-STD-750D METHOD-1031